

# Complete MOS Small-Signal Model

**Prof. Ali M. Niknejad**  
**Prof. Rikky Muller**



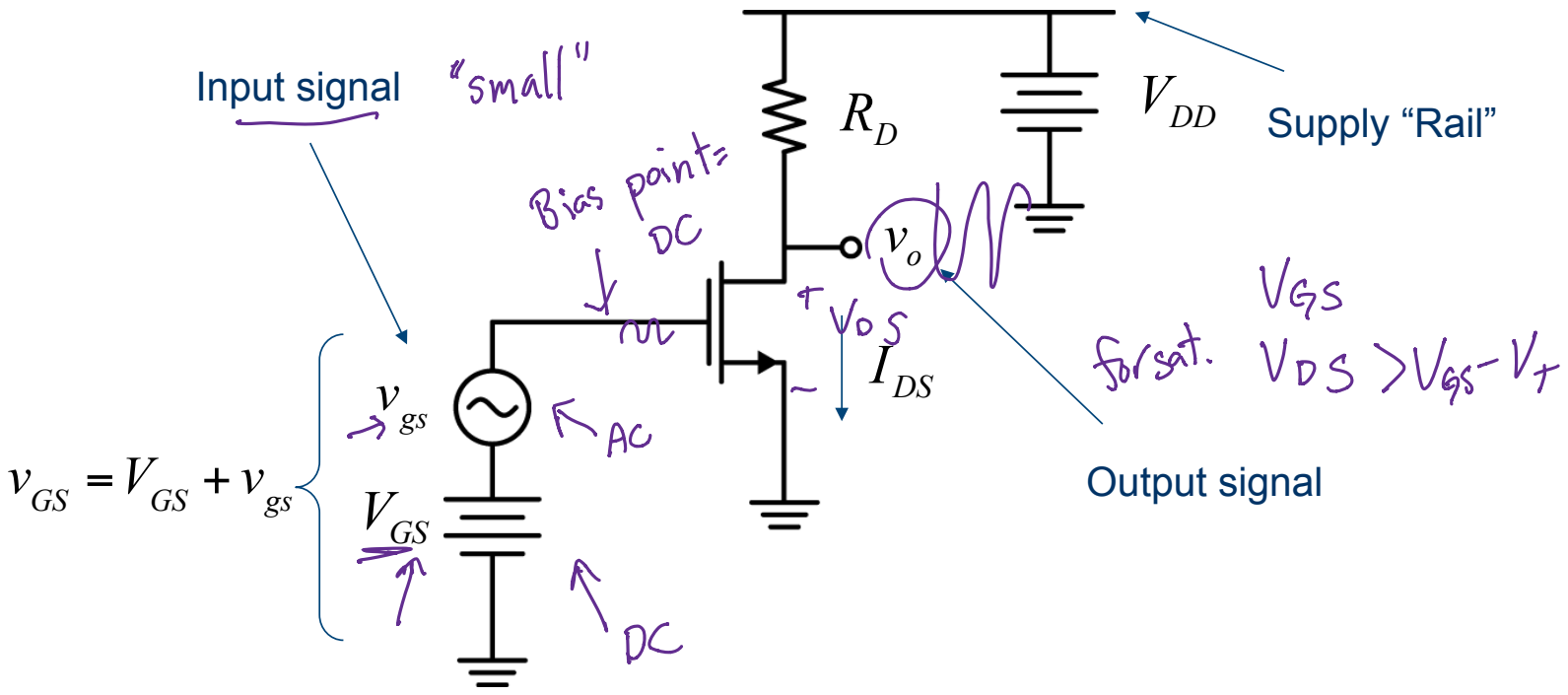
# Announcements

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- Welcome back!
- Pick up graded MT2 in lecture on Tuesday
- Check updated syllabus
- No lab this week
- HW8 due on Friday

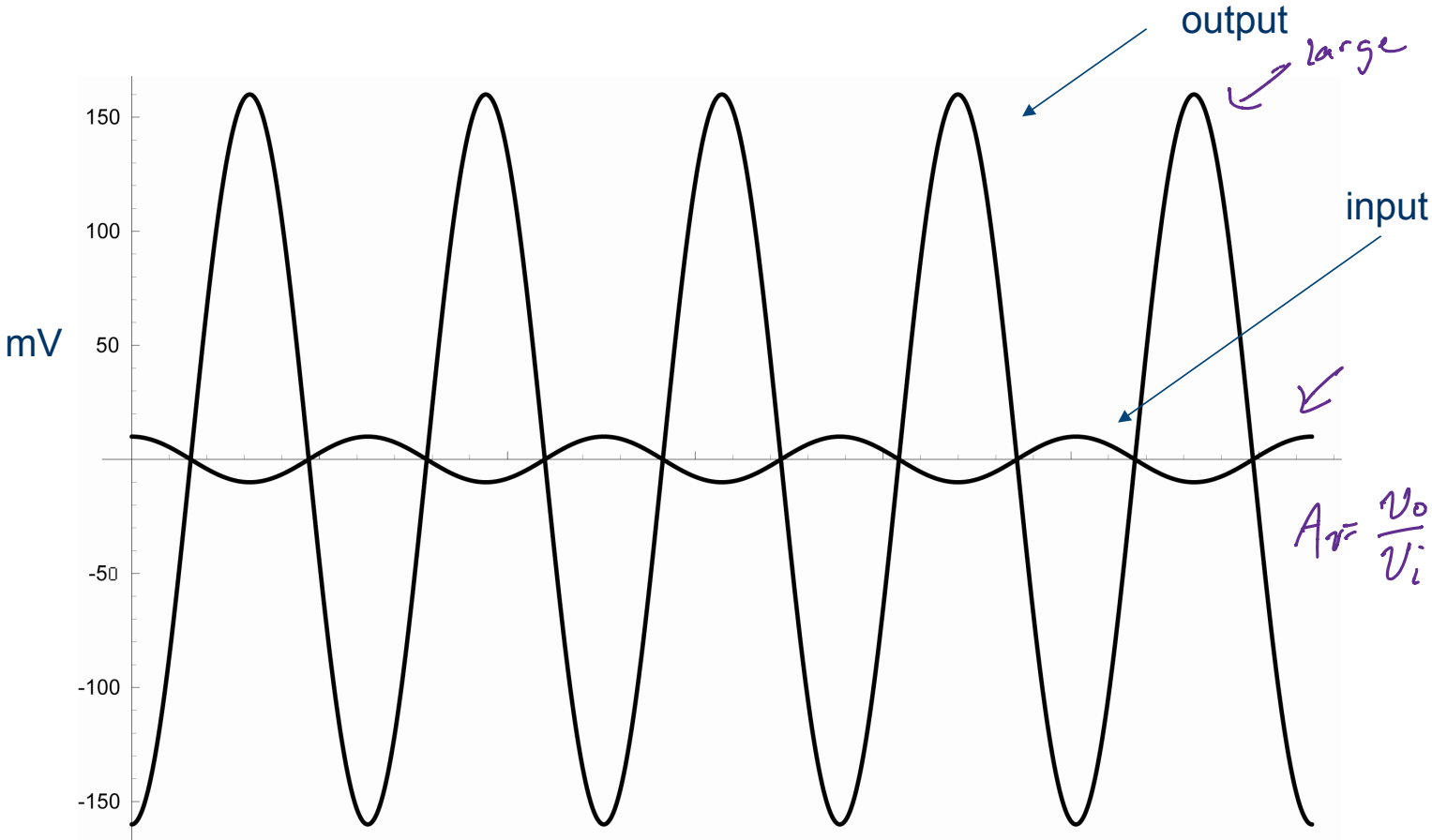
↳ AVE = 78  
 $\sigma \sim 15$

# Review: An MOS Amplifier

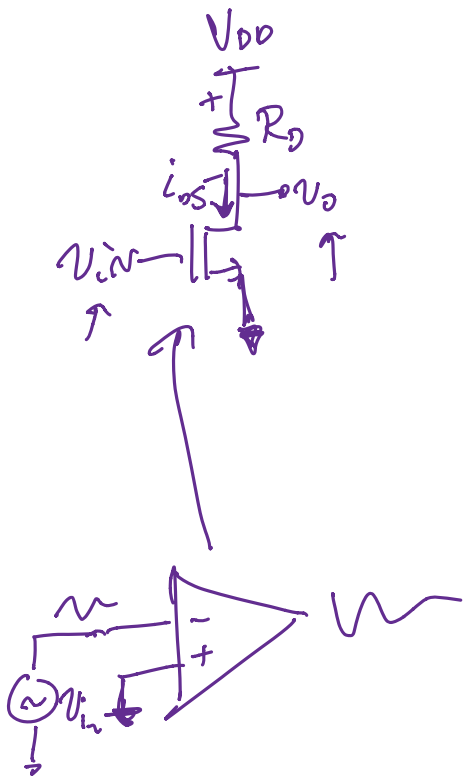


This type of amplifier is known as “Common Source (CS)”

# Plot of Output Waveform (Gain!)



# Total Small Signal Current



$$i_{DS}(t) = \underbrace{I_{DS}}_{\text{DC}} + \underbrace{i_{ds}}_{\text{AC}}$$

BIAS POINT

$$\underline{V_O = V_{DD} - I_{DS} \cdot R_D}$$

$$\underline{i_{ds}} = \frac{\partial i_{DS}}{\partial v_{gs}} v_{gs} + \frac{\partial i_{DS}}{\partial v_{ds}} v_{ds}$$

want $i_{ds}$  changes a lot  
w/  $v_{gs}$ don't want $i_{ds}$  change  
w/  $v_{ds}$ 

$$i_{ds} = g_m v_{gs} + \frac{1}{r_o} v_{ds}$$

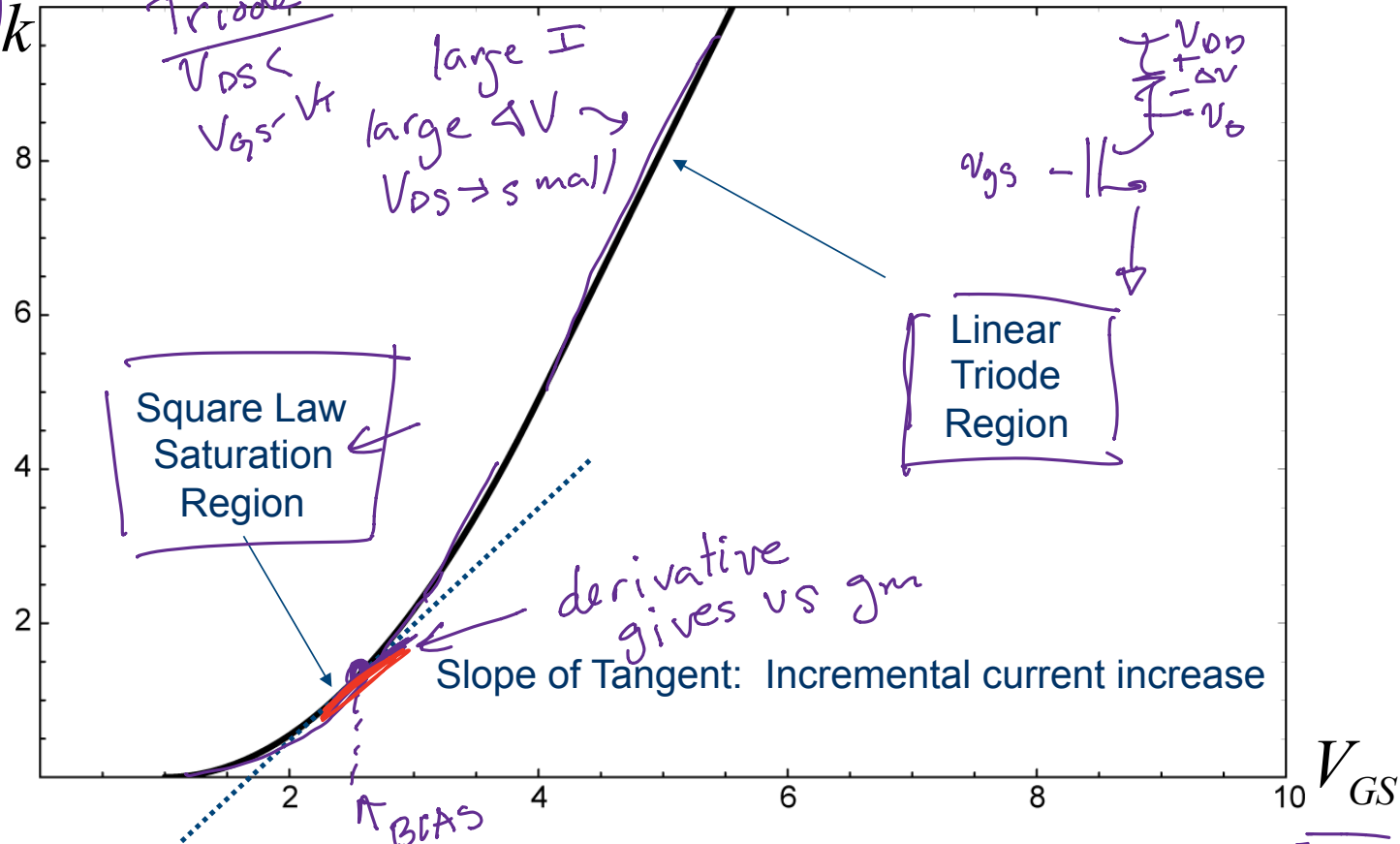
↑ large
↑ large  
↑ small
↑ small

Transconductance

Conductance

# Changing One Variable at a Time

$I_{DS} / k$



Assumption:  $V_{DS} > V_{DS,SAT} = V_{GS} - V_{Tn}$  (square law)

# The *Transconductance* $g_m$

Defined as the change in drain current due to a change in the *gate-source voltage*, with *everything else constant*

$$I_{DS,sat} = \frac{W}{L} \frac{\mu C_{ox}}{2} (V_{GS} - V_T)^2 (1 + \lambda V_{DS})$$

$\lambda \rightarrow \text{small}$

$$g_m = \frac{\Delta i_D}{\Delta v_{GS}} \Big|_{V_{GS}, V_{DS}} = \frac{\partial i_D}{\partial v_{GS}} \Big|_{V_{GS}, V_{DS}} = \mu C_{ox} \frac{W}{L} (V_{GS} - V_T) (1 + \lambda V_{DS})$$

$\approx 0$

input  $V$   
to  
output  $I$

bias point

$$g_m = \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)$$

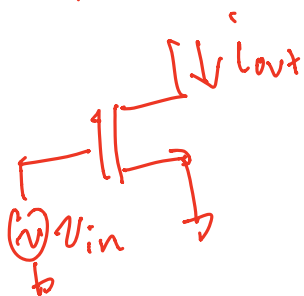
← Gate Bias

$$g_m = \mu C_{ox} \frac{W}{L} \sqrt{\frac{2I_{DS}}{\frac{W}{L} \mu C_{ox}}} = \sqrt{2\mu C_{ox} \frac{W}{L} I_{DS}}$$

← Drain Current Bias

$$g_m = \frac{2I_{DS}}{(V_{GS} - V_T)}$$

← Drain Current Bias and Gate Bias

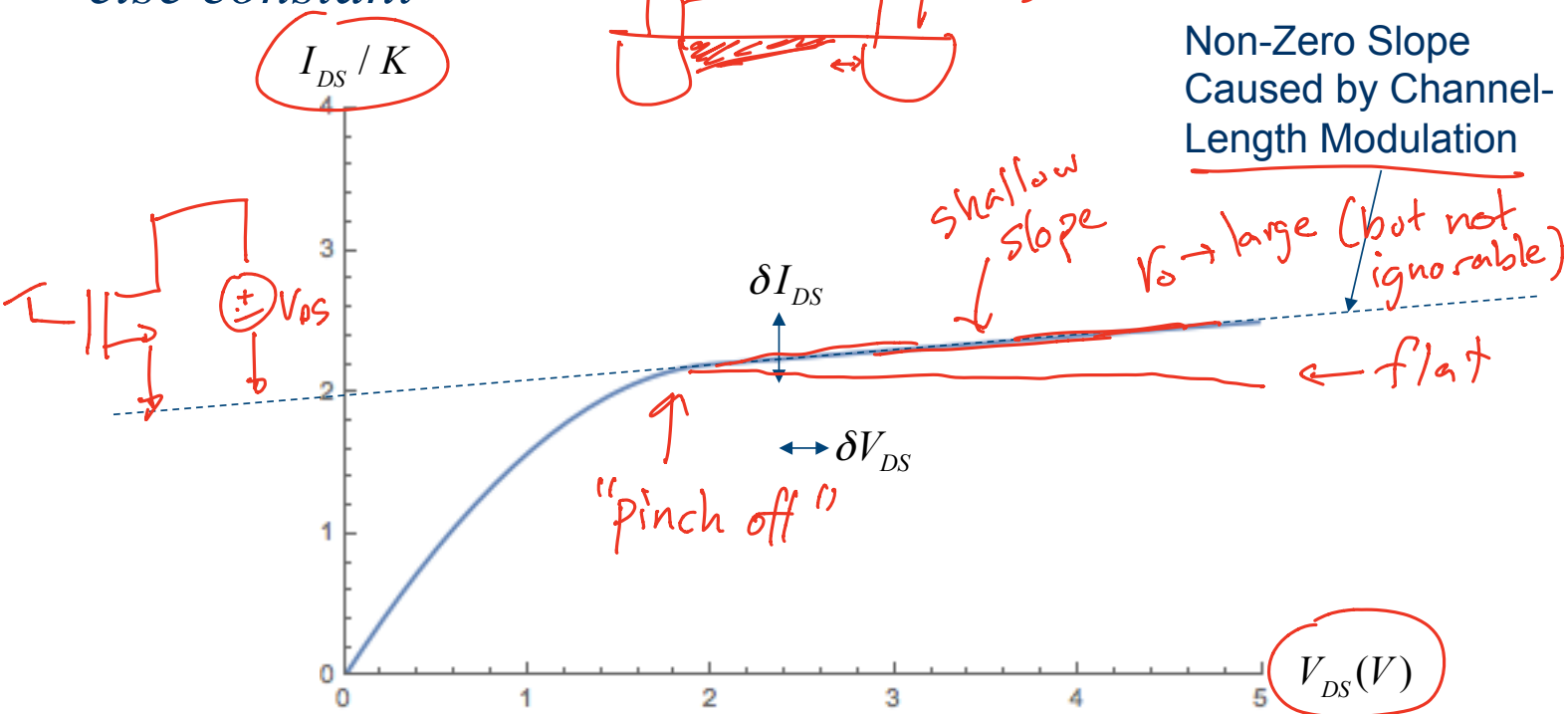


# Output Resistance $r_o$

Defined as the inverse of the change in drain current due to a change in the *drain-source* voltage, with *everything else constant*



Non-Zero Slope  
Caused by Channel-  
Length Modulation





# Evaluating $r_o$

$$\underline{i_D} = \frac{W}{L} \frac{\mu C_{ox}}{2} (V_{GS} - V_T)^2 (1 + \lambda V_{DS})$$

output  $v$  ( $v_{DS}$ )  
 $\Downarrow$   
 output  $I$

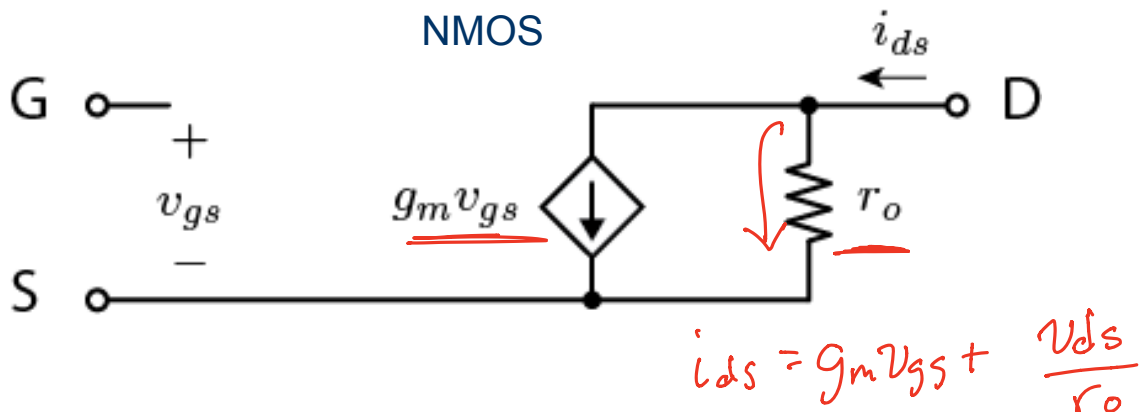
$$r_o = \left( \left. \frac{\partial i_D}{\partial v_{DS}} \right|_{V_{GS}, V_{DS}} \right)^{-1}$$

$$\Omega = \left[ \frac{\partial i_o}{\partial v_{DS}} \Rightarrow \frac{1}{\Omega} \right]^{-1}$$

$$\underline{r_o} = \frac{1}{\frac{W}{L} \frac{\mu C_{ox}}{2} (V_{GS} - V_T)^2 \lambda}$$

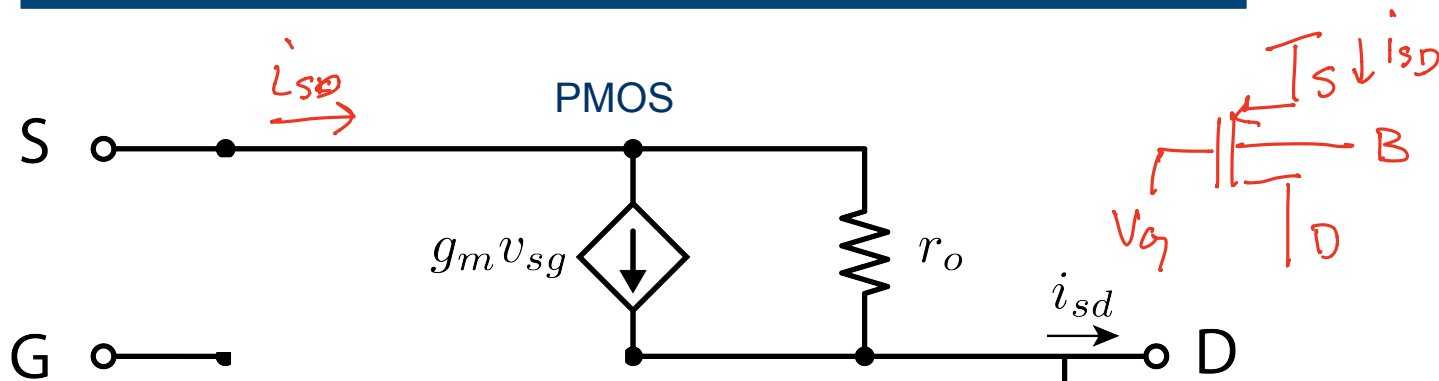
$$r_o \approx \frac{1}{\lambda I_{DS}}$$

# Simple Small Signal Model for MOSFET



- This is a simplified, 3-terminal small-signal model for a MOSFET
- In later lectures we will develop a more complete model
- $g_m$  = transconductance
  - ✍ – defined as  $di_{ds}/dv_{gs}$ , units  $[\text{Ohms}]^{-1}$
- $r_o$  = output resistance
  - ✍ – defined as  $[di_{ds}/dv_{ds}]^{-1}$ , units Ohms

# Small-Signal PMOS Model



- This is a simplified, 3-terminal small-signal model for a MOSFET
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- $g_m$  = transconductance
  - defined as  $di_{sd}/dv_{sg}$ , units  $[\text{Ohms}]^{-1}$
- $r_o$  = output resistance
  - defined as  $[di_{sd}/dv_{sd}]^{-1}$ , units Ohms

$$i_{ds} \rightarrow i_{sd}$$

$$v_{ds} \rightarrow v_{sd}$$

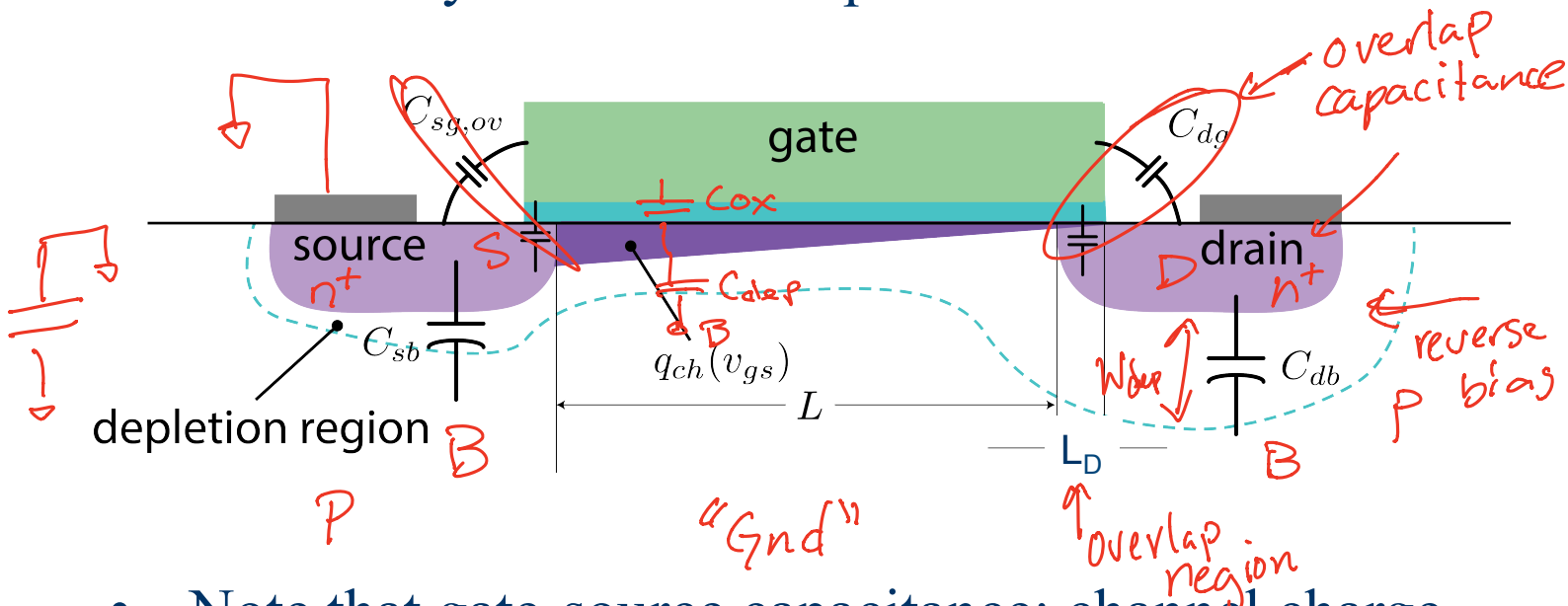
# What we've ignored...until now!

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- The fourth terminal of the MOSFET is the body of the transistor... it can act like a second gate, or “back gate”
- The junctions of the transistor form pn-junction diodes with body, this introduces parasitic capacitance

# MOSFET Capacitances in Saturation

MOSFETS have many parasitic capacitances  
Let us analyze where each parasitic comes from

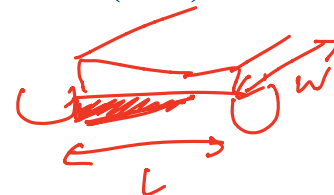


- Note that gate-source capacitance: channel charge is mostly controlled by gate-source and not drain in saturation

# Gate-Source Capacitance $C_{gs}$

Wedge-shaped charge in saturation  $\rightarrow$  effective area is  $(2/3)WL$

$$C_{gs} = \underbrace{(2/3)WL}_{\substack{\text{larger} \\ \downarrow}} \underbrace{C_{ox}}_{\substack{\downarrow \\ \text{parallel plate}}} + \underbrace{C_{ov}}$$

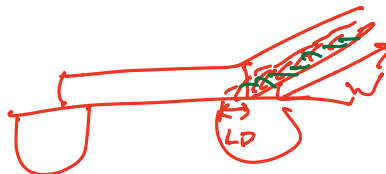


Overlap capacitance along source edge of gate  $\rightarrow$

$$C_{ov} = \underbrace{L_D}_{\text{green underline}} \underbrace{WC}_{\text{green underline}}_{ox}$$



(Underestimate due to fringing fields)



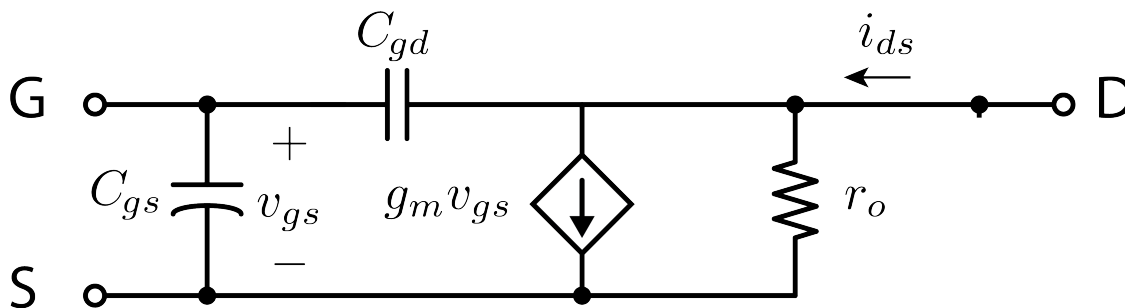
# Gate-Drain Capacitance $C_{gd}$

IN SATURATION

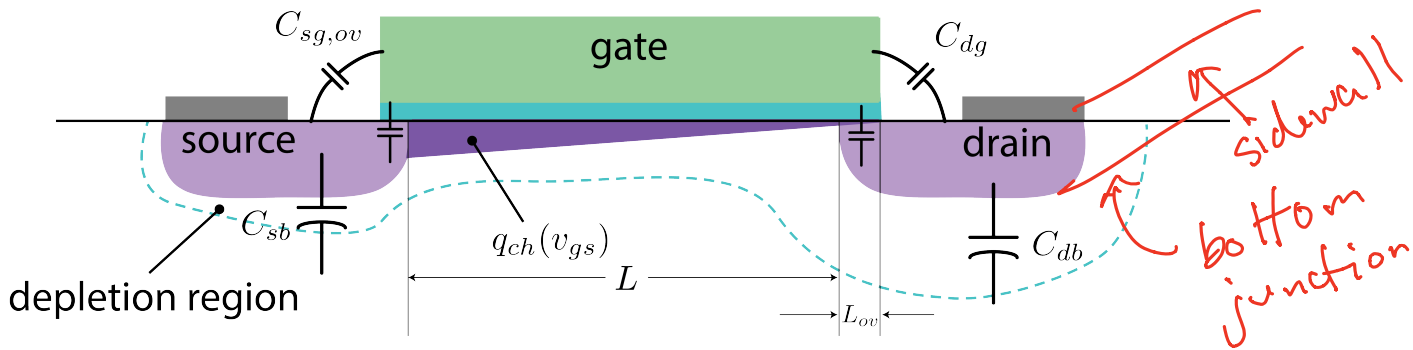
Not due to change in inversion charge in channel.

Overlap (and fringing) capacitance  $C_{ov}$  between drain and source is  $C_{gd}$

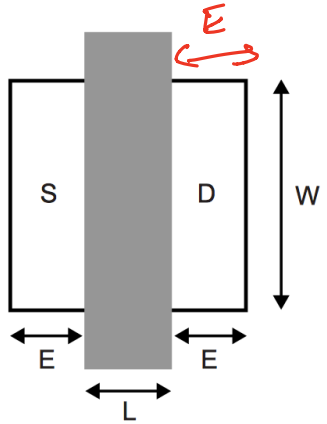
$$C_{gd} = \underline{C_{ov}} = \underline{L_D W C_{ox}}$$



# Drain-Bulk Capacitance $C_{db}$



- Drain-Bulk and Source-Bulk capacitance is caused by p-n junction depletion



junction bottom wall cap (per area)  $\leftarrow$   $C_j(0)$   
 junction sidewall cap (per length)  $\leftarrow$   $C_{jsw}(0)$

$$\text{source to bulk cap: } C_{jsb} = \frac{C_j(0)}{\sqrt{1 + V_{SB}/|\Phi_B|}} WE + \frac{C_{jsw}(0)}{\sqrt{1 + V_{SB}/|\Phi_B|}} (W + 2E)$$

$$\text{drain to bulk cap: } C_{jbd} = \frac{C_j(0)}{\sqrt{1 + V_{DB}/|\Phi_B|}} WE + \frac{C_{jsw}(0)}{\sqrt{1 + V_{DB}/|\Phi_B|}} (W + 2E)$$



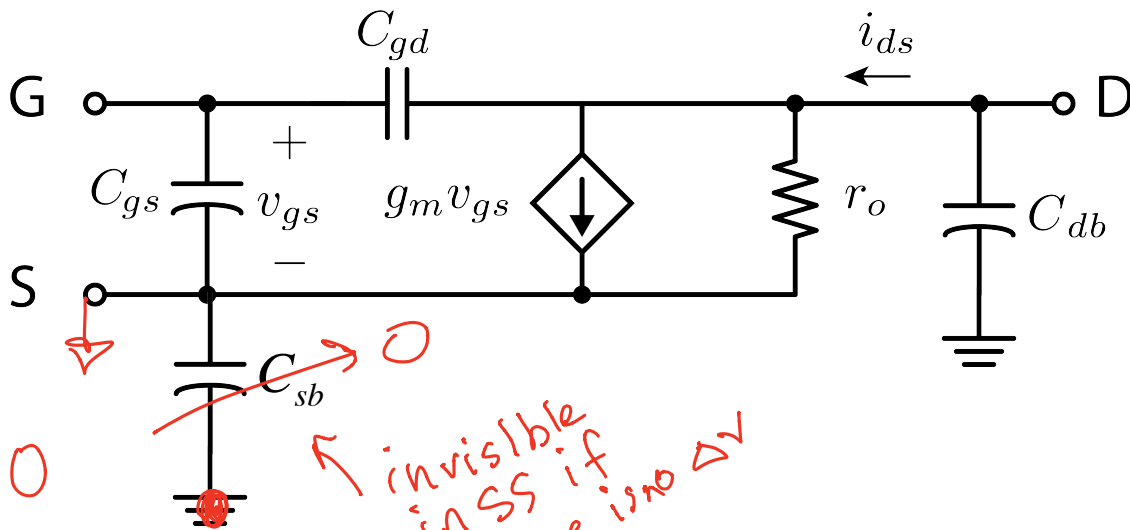
# Summary of Capacitance Models

$$C_{gs} = (2/3)WLC_{ox} + C_{ov}$$

$$C_{gd} = C_{ov}$$

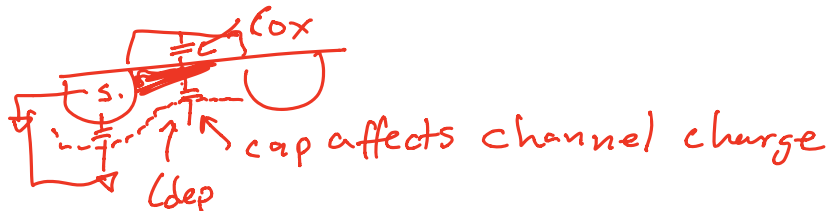
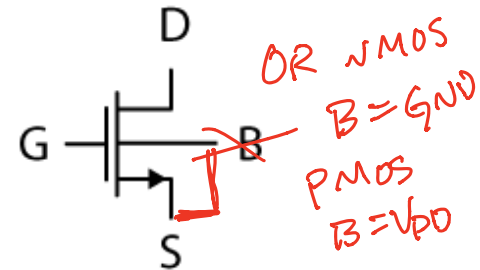
$$C_{sb} = C_{jsb} (\text{area} + \text{perimeter}) \text{ junction}$$

$$C_{db} = C_{jdb} (\text{area} + \text{perimeter}) \text{ junction}$$



# Back-Gate Effect

- Transistor really has *four* terminals:
  - Source / Drain
  - Gate / Body
- There is a symmetry between the gate and the body. The body can act like a “back gate”
- In many instances the body terminal is simply tied to the source (ground or VSS for NMOS, supply or VDD for PMOS)
- What happens if there is a DC or AC voltage swing on the body?



# Body Bias Affects $V_T$

- If there is a body bias  $V_{SB}$ , a depletion capacitance appears in parallel with  $C_{ox}$  and affects the amount of channel charge:

$$C_{dep} = \epsilon_s / x_{dep,max} \quad [F/cm^2]$$

$$Q_{inv} = -C_{ox} (V_{GS} - V_T) + C_{dep} V_{SB}$$

$$Q_{inv} = -C_{ox} \left[ V_{GS} - V_T + \frac{C_{dep}}{C_{ox}} V_{SB} \right]$$

injects additional charge

$$V_T(V_{SB}) = V_{T0} + \frac{C_{dep}}{C_{ox}} V_{SB}$$

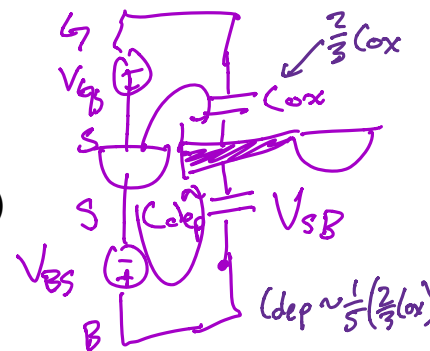
where it comes from

- $C_{dep}$  changes with body bias, if we account for this: from

$$V_{T0n} = V_{FB} - 2\phi_p + \frac{1}{C_{ox}} \sqrt{2q\epsilon_s N_a (-2\phi_p)}$$

$$\Delta V_T = \frac{1}{C_{ox}} \sqrt{2q\epsilon_s N_a} (\sqrt{-2\phi_p + V_{SB}} - \sqrt{-2\phi_p})$$

$$V_T = V_{T0} + \gamma \left( \sqrt{V_{SB} - 2\phi_p} - \sqrt{-2\phi_p} \right)$$



model

# Role of the Substrate Potential

Note: Need not be the source potential, but  $V_B < V_S$   
*don't turn on the diode!*  $V_B < V_S$  *↙ ground*

Effect: changes threshold voltage, which changes the drain current ... substrate acts like a “backgate”

$$\underline{g_{mb}} = \frac{\Delta i_D}{\Delta v_{BS}} \Big|_Q = \frac{\partial i_D}{\partial v_{BS}} \Big|_Q \quad Q = (V_{GS}, V_{DS}, \underline{V_{BS}})$$

$$\underline{g_{mb}} = \frac{\partial i_D}{\partial v_{BS}} \Big|_Q = \frac{\partial i_D}{\partial V_{Tn}} \Big|_Q \frac{\partial V_{Tn}}{\partial v_{BS}} \Big|_Q$$

$v_{bs} \rightarrow$  affects  
 $\hookrightarrow i_{ds}$

# Backgate Transconductance

$$I_D = \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^2 (1 + \lambda V_{DS})$$

$$V_T = V_{T0} + \gamma \left( \sqrt{V_{SB} - 2\phi_p} - \sqrt{-2\phi_p} \right)$$

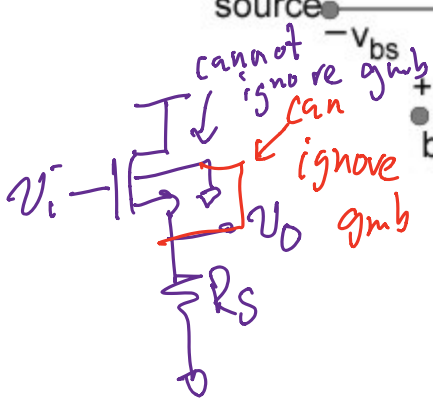
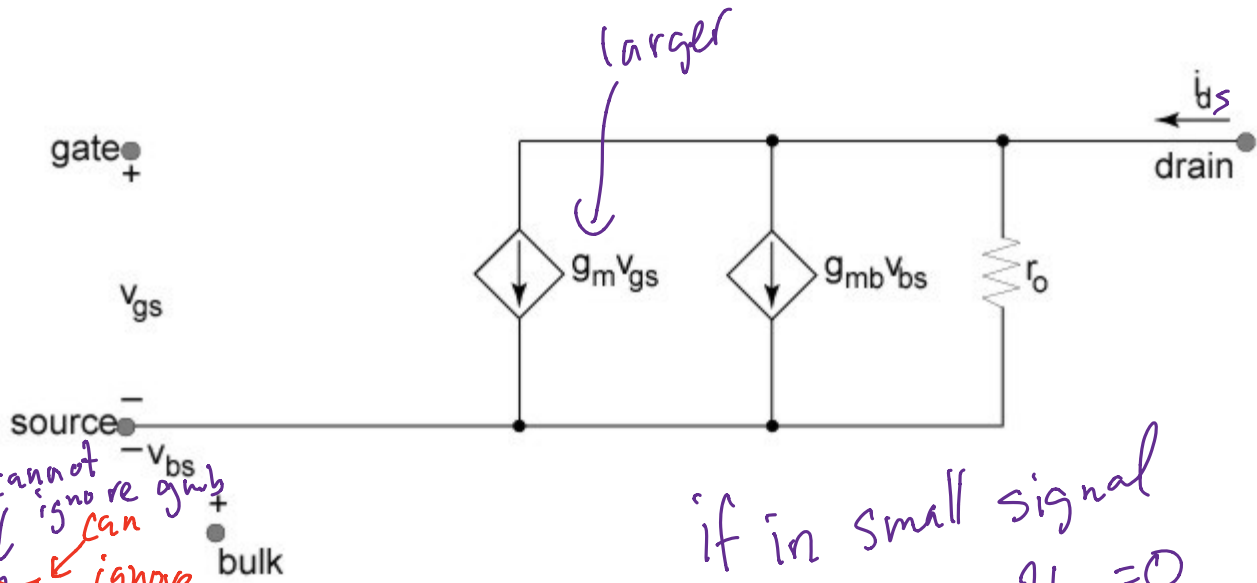
Result:

$$g_{mb} = \left. \frac{\partial i_D}{\partial v_{BS}} \right|_Q = \left. \frac{\partial i_D}{\partial V_{Tn}} \right|_Q \left. \frac{\partial V_{Tn}}{\partial v_{BS}} \right|_Q = \frac{\gamma g_m}{2\sqrt{-V_{BS} - 2\phi_p}}$$

$$\begin{aligned} \frac{\partial V_T}{\partial V_{BS}} &= \frac{\partial}{\partial V_{BS}} \left[ \gamma \left[ (-V_{BS} - 2\phi_p)^{1/2} - (-2\phi_p)^{1/2} \right] \right] \\ &= -\frac{1}{2} \gamma (-V_{BS} - 2\phi_p)^{-1/2} \end{aligned}$$

$$\begin{aligned} \frac{\partial i_D}{\partial V_T} &= \frac{\partial}{\partial V_T} \left[ \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^2 \right] \\ &= -\mu C_{ox} \frac{W}{L} (V_{GS} - V_T) = -g_m \end{aligned}$$

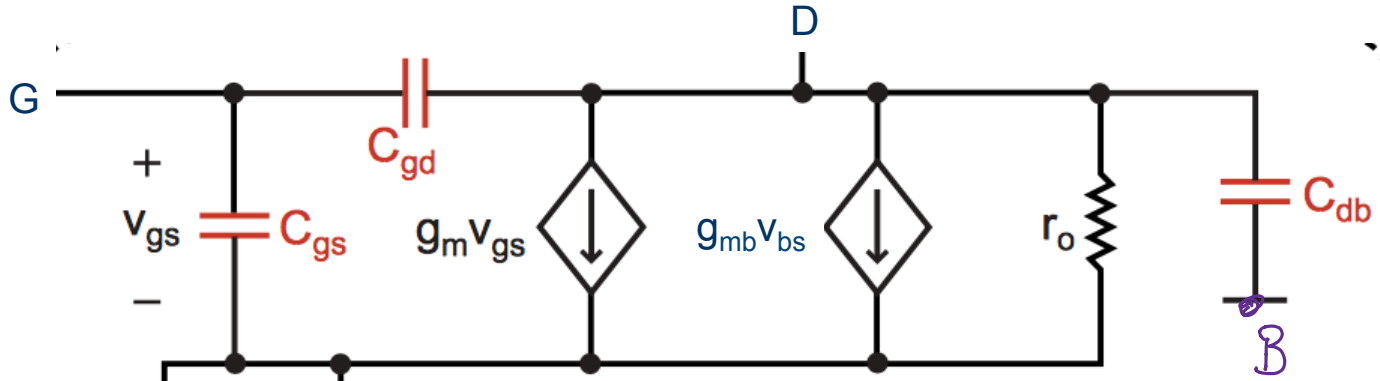
# Four-Terminal Small-Signal Model



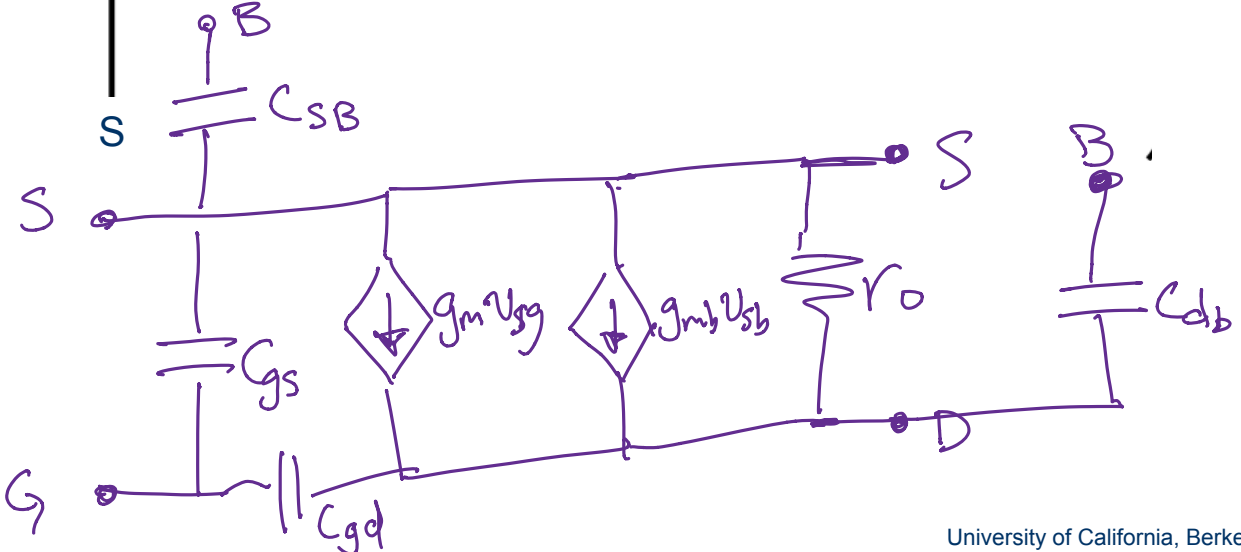
if in small signal  $v_{bs} = 0$   
 $g_{mb} v_{bs} = 0$

$$\underline{i_{ds}} = \underline{g_m v_{gs}} + \underline{g_{mb} v_{bs}} + \frac{1}{r_o} v_{ds}$$

# Complete Small-Signal Model NMOS



PMOS



# Complete Small-Signal Model PMOS

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